

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10531753	NESZ ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	SHAQ TAHA	2446

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
709	227	10/16/2008	S. Taha
709	227	03/25/2009	S. Taha
709	227	12/20/2009	S. Taha

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
EAST (USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB), see attached; NPL: IEEE; Inventor Search/DP; Text search in cls 709/223,224,225,226,228,229	09/10/2008	S. Taha
EAST (USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB), see attached; NPL: IEEE; Inventor Search/DP; Text search in cls 709/223,224,225,226,228,229	03/25/2009	S. Taha
EAST (USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB), see attached; NPL: IEEE; Inventor Search/DP; Text search in cls 709/223,224,225,226,228,229	12/20/2009	S. Taha

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

/S. T./  
Examiner.Art Unit 2446